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EMC Test Report

Applicant : Acrel Co., Ltd.

Address No.253, Yulv Road, Jiading District, Shanghai

China

Product Name : Power Meter

Report Date : Mar. 08, 2024

Shenzhen Anbotek Compliance Laboratory Limited







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TEST REPORT

Applicant : Acrel Co., Ltd.

Manufacturer : Jiangsu Acrel Electrical Manufacturing. Co., Ltd.

Product Name : Power Meter

Test Model No. : PZ96(L)-E4/*

PZ72(L)-E3/*, PZ72(L)-E4/*, PZ80(L)-E3/*, PZ80(L)-E4/*,

Reference Model No. : PZ96(L)-E3/*,PZ42(L)-E3/*,PZ42(L)-E4/*

(* indicates Z,H,K, M, C, D, F, 2C,T,LR)

Trade Mark : Acrel

Rating(s) PT: 3*230/400V, CT: 3*1(6)A Power: AC/DC 85-265V, 5W

Test Standard(s) : EN IEC 61326-1: 2021;

EN IEC 61000-3-2: 2019+A1:2021; EN 61000-3-3: 2013+A2:2021;

(IEC 61000-4-2; IEC 61000-4-3; IEC 61000-4-4;

IEC 61000-4-5; IEC 61000-4-6; IEC 61000-4-8; IEC 61000-4-11)

The device described above is tested by Shenzhen Anbotek Compliance Laboratory Limited to determine the maximum emission levels emanating from the device and the severe levels of the device can endure and its performance criterion. The measurement results are contained in this test report and Shenzhen Anbotek Compliance Laboratory Limited is assumed full of responsibility for the accuracy and completeness of these measurements. Also, this report shows that the EUT (Equipment Under Test) is technically compliant with the EN IEC 61326-1, EN IEC 61000-3-2, EN 61000-3-3 requirements.

This report applies to above tested sample only and shall not be reproduced in part without written approval of Shenzhen Anbotek Compliance Laboratory Limited.

Date of Receipt:	Feb. 26, 2024
Date of Test:	Feb. 26~Mar. 05, 2024
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Prepared By:	arek Os h
	(We Zeng)
	(ingkonf)in
Approved & Authorized Signer:	The state of the s
All otek Anboten Anbo ok botek Anbo	(KingKong Jin)





Code: AB-EMC-02-c



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1. General Information

1.1. Client Information

Applicant	Acrel Co., Ltd.
Address	No.253, Yulv Road, Jiading District, Shanghai China
Manufacturer	Jiangsu Acrel Electrical Manufacturing. Co., Ltd.
Address	No.5, Dongmeng Road, Nanzha Street, Jiangyin City Jiangsu Province, China
Factory	Jiangsu Acrel Electrical Manufacturing. Co., Ltd.
Address	No.5, Dongmeng Road, Nanzha Street, Jiangyin City Jiangsu Province, China

1.2. Description of Device (EUT)

Product Name	:	Power Meter
Test Model No.	:	PZ96(L)-E4/*
Reference Model No.	:	PZ72(L)-E3/*, PZ72(L)-E4/*, PZ80(L)-E3/*, PZ80(L)-E4/*, PZ96(L)-E3/*,PZ42(L)-E3/*,PZ42(L)-E4/* (* indicates Z,H,K, M, C, D, F, 2C,T,LR) (Note: All samples are the same except the model number, so we prepare "PZ96(L)-E4/*" for test only.)
Trade Mark	:	Acrel Anbotek Anbotek Anbotek Anbotek Anbotek
Test Power Supply	:	AC 400V, 50Hz
Test Sample No.	:	1-1-1 Anbotek Anbotek Anbotek Anbotek Anbotek Anbotek
Product	:	N/A And sek shortek Anbol Anbole Anbole Anbole
Description		abotek Anbort All botek Anbotek Anbotek Ar

Remark: (1) For a more detailed features description, please refer to the manufacturer's specifications or the User's Manual.

1.3. Auxiliary Equipment Used During Test

N/A Anbotek Anbotek

Code: AB-EMC-02-c
Hotline
400-003-0500





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1.4. Description of Test Mode

Pretest Mode	Description					
Mode 1	Anborek	Aupor	On	Anboren	Aup	D.C

For Mode 1 Block Diagram of Test Setup



1.5. Test Summary

Test Items	Test Mode	Status
Power Line Conducted Emission Test	Mode 1	botek P Anbote
Radiated Emission Test (Below 1 GHz)	Mode 1	Anbore P Ani
Harmonic Current Test	hbotek Anbotek	AU NOK
Voltage Fluctuations & Flicker Test	Anbotek / Anbo	ek Nobotek
Electrostatic Discharge Immunity Test	Mode 1	Anbotek P Anbote
RF Field Strength Immunity Test	Mode 1	Anbotek Anb
Electrical Fast Transient/Burst Immunity Test	Mode 1	Potek
Surge Immunity Test	Mode 1	otek PAnbotek
Injected Currents Susceptibility Test	Mode 1	ambotek P Ambo
Power frequency Magnetic Field Immunity Test	Mode 1	AnboPk A
Voltage Dips and Interruptions Immunity Test	Mode 1	k Martek
P) Indicates "PASS".	botek Ant	oter Anbu

F) Indicates "Fail".

Shenzhen Anbotek Compliance Laboratory Limited



N) Indicates "Not applicable".



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1.6. Test Equipment List

	V. 11.	100			V11.	-0.5
Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
An 1.	Three Phase V-type Artificial Power Network	CYBERTEK	EM5040DT	E215040D T001	Jul. 05, 2023	1 Year
2.	EMI Test Receiver	Rohde & Schwarz	ESCI	100627	Oct. 12, 2023	1 Year
3.of	Software Name EZ-EMC	Farad Technology	ANB-03A	N/A	N/A	N/A
4.	L.I.S.N. Artificial Mains Network	Rohde & Schwarz	ENV216	100055	Oct. 12, 2023	1 Year

□ Radiated Emission Test (Below 1 GHz)

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.00	EMI Test Receiver	Rohde & Schwarz	ESPI7	101340	Feb. 22, 2024	1 Year
2.	Pre-amplifier	Emtrace	RP01A	00517	Feb. 04, 2024	1 Year
3.	Bilog Broadband Antenna	Schwarzbeck	VULB9163	01471	Feb. 25, 2023	2 Year
4.	Software Name EZ-EMC	Farad Technology	ANB-03A	N/A	N/A	N/A

☐ Harmonic Current and Flicker Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
Inbole 1.	Programmable AC Power source	IVYTECH	APS-5005A	632734	Oct. 12, 2023	1 Year
2. 📈	Harmonic and Flicker Analyzer	EMC-PARTNER	HMONICS 1000-1P	ote ³⁴ 164 Ani	Oct. 12, 2023	1 Year
3.	Harmonics-1000	N/A	Ed.3.0+4.0	N.A	N/A	botek N/A Anbi

⊠ Electrostatic Discharge Immunity Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
Ant.	ESD Simulators	emtest	ESD NX30.1	11936	Mar. 17, 2023	1 Year







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⊠ RF Field Strength Immunity Test

		- AP	V. LaC'	DV.	10	
Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1,50	Signal Generator	Agilent	N5181A	MY5014310 7	Apr. 20, 2023	1 Year
2.	Power Meter	Agilent	E4417A	MY4510138 4	Apr. 20, 2023	1 Year
3.	Amplifier	Micotop	MPA-80-100 0-600	MPA211031 8	Apr. 20, 2023	1 Year
4.	Amplifier	Micotop	MPA-1000-6 000-100	MPA211032 7	Apr. 20, 2023	1 Year
5. ^{nb}	LogPerAntenna	Schwarzbeck	VULP 9118E	01012	N/A	N/A
6.	Microwave LogPer. Antenna	Schwarzbeck	STLP 9149	00788	N/A	N/A
7.	Power Sensor	KEYSIGHT	E9323A	US40410647	Apr. 20, 2023	1 Year
8.	Power Sensor	KEYSIGHT	E9323A	MY5310000 7	Apr. 20, 2023	1 Year
9.	Electric field Probe	Narda S.T.S /PMM	EP 601	811ZX10351	Apr. 20, 2023	1 Year
10.	Software	EMtrace	EM 3	Die V Die	N/A	N/A

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
abbiek	Surge Generator	TESEQ	NSG 3060	1480	Oct. 12, 2023	1 Year
2.	CDN	TESEQ	CDN 3061	1408	Oct. 12, 2023	1 Year
3.	EFT-Clamp	PRIMA	EFT-Clamp	L burn	Oct. 12, 2023	1 Year

⊠ Surge Immunity Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
M _{po,}	Combined Wave Lightning Surge Simulator	3Ctest	CCS600	ES3771702	Jul. 05, 2023	1 Year
2.	Three Phase Power Coupling Network	3Ctest	SEPN69100 T	ES0801757	Jul. 05, 2023	1 Year
3.*	Telecom port surge generator	PMI	TW101	190411	Apr. 20, 2023	1 Year







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⊠ Injected Currents Susceptibility Test

			M. and	10%	1/60	
Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1. ^{Anh}	C/S Conducted Immunity Test System	FRANKONIA	CIT-10	126A1196/20 12	Oct. 12, 2023	1 Year
2.	CDN Anto	FRANKONIA	CDN - M2+ M3	A2210178/20 12	Oct. 12, 2023	1 Year
3.	6dB Attenuator	FRANKONIA	DAM 26W	1172202	Oct. 12, 2023	1 Year
4.	CIT-10	FRANKONIA	Version1.1.7	N/A	N/A	N/A
5.	EM-Clamp	FRANKONIA	EMCL-20	18101728-01 03	Apr. 20, 2023	1 Year

□ Power frequency Magnetic Field Immunity Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
Anbox 1.1b	Power Frequency Magnetic Field Generator	EVERFINE	EMS61000-8 K	906002	Oct. 12, 2023	1 Year

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
nbotek	CYCLE SAG	PRIMA	DRP61011A	DD12046224	Oct. 12, 2023	1 Year
NO.	Simulator	Anv PRIIVIA	G.nbo	PK 12040234	Oct. 12, 2023	inteal





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1.7. Description of Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

FCC-Registration No.: 434132

Shenzhen Anbotek Compliance Laboratory Limited, EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration No. 434132.

ISED-Registration No.: 8058A

Shenzhen Anbotek Compliance Laboratory Limited, EMC Laboratory has been registered and fully described in a report filed with the (ISED) Innovation, Science and Economic Development Canada. The acceptance letter from the ISED is maintained in our files. Registration 8058A.

Test Location

Shenzhen Anbotek Compliance Laboratory Limited.

1/F, Building D, Sogood Science and Technology Park, Sanwei community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China.





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1.8. EMS Performance Criteria

Performance criterion A

The equipment shall continue to operate as intended during and after the test. No degradation of performance or loss of function is allowed below a performance level specified in the user documentation, when the equipment is used as intended. In the case of applying immunity tests with continuous electromagnetic phenomena, the performance level may be replaced by a permissible loss of performance which shall recover, v/ithout user intervention. A permissible loss of performance is allowed within the performance level only when this information is clearly provided to the end user via documentation, such as the product user manual. No change in the operating state is allowed nor is loss of data.

Performance criterion B

The equipment shall continue to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified in the user documentation, when the equipment is used as intended. During the test, the equipment performance level may be replaced by a permissible loss of performance if such loss of performance is detailed in the EMC test plan. A permissible loss of performance is allowed within the performance level only when this information is clearly provided to the end user via documentation, such as the product user manual. An unintended change of the operating state is allowed if self-recoverable. No loss of stored data is allowed.

Performance criterion C

Loss of function is allowed, provided the function is self-recoverable or can be restored by the operation of the controls. Recovery procedure shall be included in the user documentation. No permanent damage to the equipment is allowed.







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2. Power Line Conducted Emission Test

2.1. Test Standard and Limit

	DUL	100	200.	be.	1-010	VILLE	You	200
¥	Test S	Standard:	100	EN IEC 61326-1	Ann	Anbotek	Aupo.	br.
				4.62.1		- 17	1-01	12/7

☐ Limits for conducted emission at the AC mains power ports of Class A Group 1 equipment

		V. 1.1.	No.	- 100	V-		4.17
Frequency range		Rated power≤20KVA		20KVA <rated power≤75kva<="" th=""><th colspan="2">75KVA<rated power<="" th=""></rated></th></rated>		75KVA <rated power<="" th=""></rated>	
	(MHz)	QP(dBuV)	AVG(dBuV)	QP(dBuV)	AVG(dBuV)	QP(dBuV)	AVG(dBuV)
-	0.15 ~ 0.50	ek 79 mbot	66	100	90	130	120
o'	0.50 ~ 5.00	notek 73	otek 60 Ant	86	botek 76 Arib	125	115
	5.00 ~ 30.00	73	60	90 ~ 73*	80 ~ 60*	115	105

Remark:

- (1) The lower limit shall apply at the transition frequencies.
- (2) The limit decreases linearly with the logarithm of the frequency in the range 5.00 MHz to 30.00 MHz.

☐ Limits for conducted emission at the DC power ports of Class A Group 1 equipment

Frequency range	Rated power	er≤20KVA	20KVA <rated< th=""><th>power≤75KVA</th><th>75KVA<r< th=""><th colspan="2"><rated power<="" th=""></rated></th></r<></th></rated<>	power≤75KVA	75KVA <r< th=""><th colspan="2"><rated power<="" th=""></rated></th></r<>	<rated power<="" th=""></rated>	
(MHz)	QP(dBuV)	AVG(dBuV)	QP(dBuV)	AVG(dBuV)	QP(dBuV)	AVG(dBuV)	
0.15 ~ 5.00	97 ~ 89*	84 ~ 76*	116 ~ 106*	106 ~ 96*	132 ~ 122*	122 ~ 112*	
5.00 ~ 30.00	89	76	106 ~ 89*	96 ~ 76*	122 ~ 105*	112 ~ 92*	

Remark:

The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 30.00 MHz.

□ Limits for conducted emission at the AC mains power ports of Class B Group 1 equipment

Frequency range	Limit (d	Limit (dBuV)					
(MHz)	Quasi-peak	Average					
0.15 ~ 0.50	66 ~ 56*	56 ~ 46*					
0.50 ~ 5.00	Mark 56 books	tek Anbotek 46 Anbotek					
5.00 ~ 30.00	K Anbotek 60 Anbot	botek Anbotes Anbotek					

Remark:

- (1) The lower limit shall apply at the transition frequencies.
- (2) The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.50 MHz.





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Limits for conducted emission at the DC power ports of Class B Group 1 equipment

Frequency range	Limit (dBuV)
(MHz)	Quasi-peak	Average
0.15 ~ 0.50	84 ~ 74*	74 ~ 64*
0.50 ~ 30.00	74	64 _{mb} otel And

Remark:

The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.50 MHz.

☐ Limits for conducted emission at the AC mains power ports of Class B Group 2 equipment

Frequency range	Limit (dBuV)				
(MHz)	Quasi-peak	Average			
0.15 ~ 0.50	66 ~ 56*	56 ~ 46*			
0.50 ~ 5.00	Anbotek 56 inbo	porek Anbore 46			
5.00 ~ 30.00	lek Anbotek 60 Anbo ntek	Anborek Anborek			

Remark:

- (1) The lower limit shall apply at the transition frequencies.
- (2) The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.50 MHz.

☐ Limits for conducted emission at the AC mains power ports of Class A Group 2 equipment

1-0'	162		L.O.1 D.1	1/2
Frequency range	Limit of Rated powe	r≤75KVA (dBuV)	Limit of Rated power	er>75KVA (dBuV)
(MHz)	Quasi-peak	Average	Quasi-peak	Average
0.15 ~ 0.50	100	90	130	120
0.50 ~ 5.00	86	76	125	115
5.00 ~ 30.00	90 ~ 73*	80 ~ 60*	otel 115 10010	105

Remark:

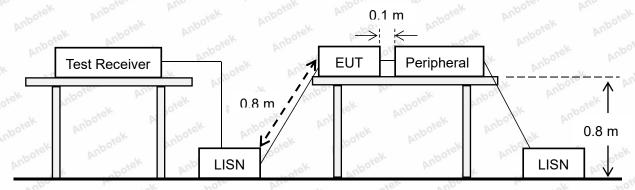
- (1) The lower limit shall apply at the transition frequencies.
- (2) The limit decreases linearly with the logarithm of the frequency in the range 5.00 MHz to 30.00 MHz.





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2.2. Test Setup



2.3. Test Procedure

The table-top EUT is placed on a non-conductive table 0.8 m above the horizontal ground reference plane, and the back of the EUT is 0.4 m away from the vertical ground reference plane, and at least 0.8 m from any other metal surface or ground plane. The floor-standing EUT is placed on an insulating support 0.1 m above the horizontal ground reference plate, at least 0.8 m away from other metal objects.

Connect EUT to the power mains through an LISN. Where the mains cable supplied by the manufacturer is longer than 1 m, the excess should be folded at the center into a bundle no longer than 0.4 m, so that its length is shortened to 1 m. All the peripherals are connecting to the other LISN.

The initial testing identified the frequency that has the highest disturbance relative to the limit while operating the EUT in typical modes of operation and cable positions in a test setup representative of typical system configuration.

The identification of the frequency of highest disturbance with respect to the limit was found by investigating disturbances at a number of significant frequencies. The probable frequency of maximum disturbance had been found and that the associated cable and EUT configuration and mode of operation had been identified.

Set the test-receiver to quasi peak detect function and average detect function, and to measure the conducted emissions values.

2.4. Test Results

PASS

The test curves are shown in the following pages.





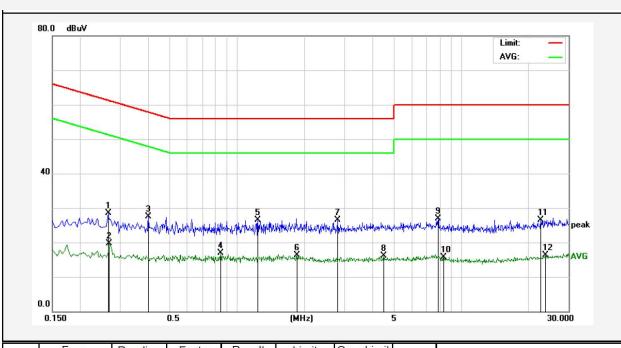


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Power Line Conducted Test Data

Test Site: 1# Shielded Room
Test Specification: AC 400V, 50Hz
Comment: Live Line1

Temp.: 23.5℃ Hum.: 45%



No.	Freq. (MHz)	Reading (dBuV)	Factor (dB)	Result (dBuV)	Limit (dBuV)	Over Limit (dB)	Detector	Remark
1	0.2660	9.45	19.02	28.47	61.24	-32.77	QP	
2	0.2700	0.61	19.02	19.63	51.12	-31.49	AVG	
3	0.4020	8.54	19.00	27.54	57.81	-30.27	QP	
4	0.8460	-2.03	18.99	16.96	46.00	-29.04	AVG	
5	1.2420	7.55	18.93	26.48	56.00	-29.52	QP	
6	1.8500	-2.67	18.88	16.21	46.00	-29.79	AVG	
7	2.8220	7.73	18.86	26.59	56.00	-29.41	QP	
8	4.5060	-2.78	18.81	16.03	46.00	-29.97	AVG	
9	7.8700	8.16	18.78	26.94	60.00	-33.06	QP	
10	8.3260	-3.05	18.78	15.73	50.00	-34.27	AVG	
11	22.5780	7.74	18.84	26.58	60.00	-33.42	QP	
12	23.7460	-2.49	18.84	16.35	50.00	-33.65	AVG	

Note: Result = Reading + Factor Over Limit = Result - Limit





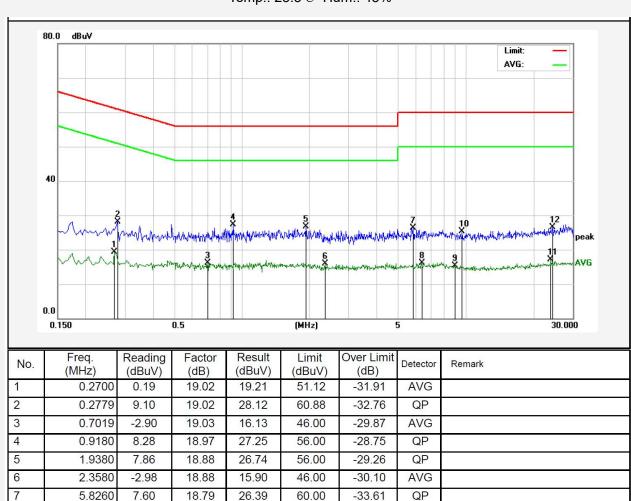


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Power Line Conducted Test Data

Test Site: 1# Shielded Room
Test Specification: AC 400V, 50Hz
Comment: Live Line2

Temp.: 23.5℃ Hum.: 45%



Note: Result = Reading + Factor Over Limit = Result - Limit

18.78

18.78

18.78

18.84

18.83

16.07

15.39

25.28

17.04

26.47

50.00

50.00

60.00

50.00

60.00

-33.93

-34.61

-34.72

-32.96

-33.53

AVG

AVG

QP

AVG

QP





6.3380

8.9020

9.6380

23.9860

24.4020

-2.71

-3.39

6.50

-1.80

7.64

8

9

10

11

12

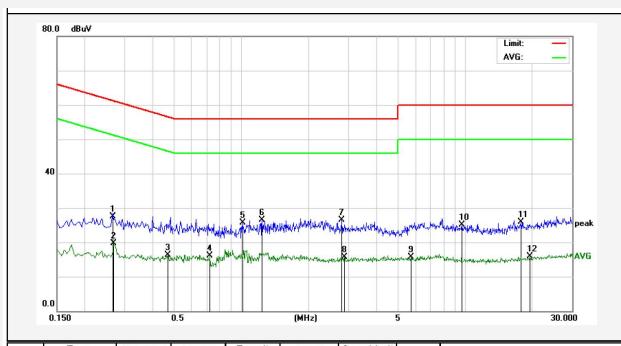


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Power Line Conducted Test Data

Test Site: 1# Shielded Room
Test Specification: AC 400V, 50Hz
Comment: Live Line3

Temp.: 23.5℃ Hum.: 45%



No.	Freq. (MHz)	Reading (dBuV)	Factor (dB)	Result (dBuV)	Limit (dBuV)	Over Limit (dB)	Detector	Remark
1	0.2671	8.58	19.02	27.60	61.20	-33.60	QP	
2	0.2700	0.61	19.02	19.63	51.12	-31.49	AVG	
3	0.4698	-2.83	19.09	16.26	46.52	-30.26	AVG	
4	0.7258	-2.85	19.02	16.17	46.00	-29.83	AVG	
5	1.0140	6.75	18.95	25.70	56.00	-30.30	QP	
6	1.2419	7.55	18.93	26.48	56.00	-29.52	QP	
7	2.8220	7.73	18.86	26.59	56.00	-29.41	QP	
8	2.8860	-3.16	18.86	15.70	46.00	-30.30	AVG	
9	5.7298	-3.17	18.79	15.62	50.00	-34.38	AVG	
10	9.6897	6.27	18.78	25.05	60.00	-34.95	QP	
11	17.8297	7.01	18.85	25.86	60.00	-34.14	QP	
12	19.4939	-3.01	18.86	15.85	50.00	-34.15	AVG	

Note: Result = Reading + Factor Over Limit = Result - Limit





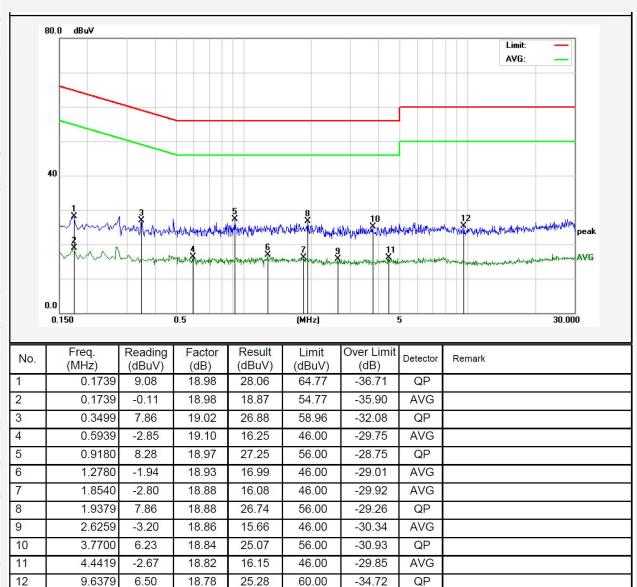


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Power Line Conducted Test Data

Test Site: 1# Shielded Room
Test Specification: AC 400V, 50Hz
Comment: Neutral Line

Temp.: 23.5℃ Hum.: 45%



Note: Result = Reading + Factor Over Limit = Result - Limit







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3. Radiated Emission Test (Below 1 GHz)

3.1. Test Standard and Limit

	VUS		100	200.	Pr. V	1-01	VILLE	You	200
K		Test Stan	dard	10	EN IEC 61326-1	And	Anbotek	Anbo	by.
		-\/-	10°C,	Direct	74.Q.	- 40		VC ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~	565

□ Limit for radiated emissions at frequencies up to 1 GHz for class A Group 1 equipment

Limit of Rated power≤20KVA (3m) Quasi-peak (dBuV/m)				Limit of Rated power>20KVA (3m) Quasi-peak (dBuV/m)			
Anborek	57	otek	Anbo	lek but	60	botek	Anbo
		Quasi-peak (c	Quasi-peak (dBuV/m	Quasi-peak (dBuV/m)	Quasi-peak (dBuV/m) Qu	Quasi-peak (dBuV/m) Quasi-peak (Quasi-peak (dBuV/m) Quasi-peak (dBuV/m) 50 60

Remark: The lower limit shall apply at the transition frequencies.

Frequency (MHz)	Distance (Meters)	Field Strengths Limit (dBμV/m)		
30 ~ 230	potek Anborg Anborgek	40		
230 ~ 1000	upotek Arguer And	Anborek 47 Anbourtek		
Remark: The lower limit shall	I apply at the transition frequencies.	otek Anbotek Anbo		

☐ Limit for radiated emissions at frequencies up to 1 GHz for class B Group 2 equipment

Frequency	Limit (3m)					
(MHz)	QP	AVG	QP			
(1411 12)	(dBμV/m)	(dBμV/m)	(dBμA/m)			
0.15 ~ 30	Anbotek _ Anbot	k vupatek vu	39 ~ 3*			
30 ~ 80.872	40	35	Anbore Ansotek			
80.872 ~ 81.848	60	55, 100 181	Anbotek- Anbotek			
81.848 ~ 134.786	40	Anbotek 35 Anbote	k abotek Anbo			
134.786 ~ 136.414	Anboree 60 Anborek	Anbore 55 Anbor	otek anbotek Ar			
136.414 ~ 230	40	35	hotek Anbotek			
230 ~ 1000	47	42	and abotek - Anbotek			

Remark:

- (1) The lower limit shall apply at the transition frequencies.
- (2) The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 30 MHz.

Code: AB-EMC-02-c
Hotline
400-003-0500





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☐ Limit for radiated emissions at frequencies up to 1 GHz for class A Group 2 equipment

Frequency	Limit	(3m)		
(MHz)	QP	QP		
· · · · - /	(dBμV/m)	(dBμA/m)		
0.15 ~ 0.49	Latek Anbasek Anbo	And Andrew And		
0.49 ~ 1.705	And otek Anbotek Anbo	ak Anbotek 72 Anbotes A		
1.705 ~ 2.194	Anbotek - Anbotek Anbo	tek nbore 77 Anbore		
2.194 ~ 3.95	And hotek - Anbotek Ar	otek Anbore		
3.95 ~ 11	Anbotek- Anbotek	68 ~ 28.5*		
11 ~ 20	port An abotek Anbotek	28.5 orek		
20 ~ 30	Anbor Anborek Anborer	And hotek 18.5 Anbotek Ar		
30 ~ 47	Anborek 78 borek Anborek	Anbotek - Anbotek		
47 ~ 53.91	Anbotek 60 Anbotek An	port An. abotek Anboten		
53.91 ~ 54.56	Ann hotel 60 Anbotek	Anborek Anborek Anbore		
54.56 ~ 68	60 Anborek	Anbo atek anbotek Anbo		
68 ~ 80.872	Anbotek 73,ek Anbotek	Anbotek - anbotek An		
80.872 ~ 81.848	Anbor 88 borek Anbor	Anbotek - Anbotek		
81.848 ~ 87	Anbottek 73 nbotek Ant	ore And hotek Anborek		
87 ~ 134.786	Anboarek 70 Anbotek	Anbore And Anborek		
134.786 ~ 136.414	80 Anborek	Anbor Anborek Anbor		
136.414 ~ 156	nbore Anb 70ek Anborek	Anbo. Anbotek An		
156 ~ 174	Ambore 84 Amborek Amborek	Anbotek - Anbotek		
174 ~ 188.7	Augo 60 Mark Mul	otek Anbo		
188.7 ~ 190.979	Anbore 70 Anborek	nbotek Anbotek		
190.979 ~ 230	60 Model	Anbores Anborek Anbore		
230 ~ 400	hotek Anbarra Anbarek	Anboron Anb		
400 ~ 470	Anborek Anton Anborel	Aupotes Aug		
470 ~ 1000	Anborek 70 borek Anbr	lek Aupon Au Motek		

Remark:

- (1) The lower limit shall apply at the transition frequencies.
- (2) The limit decreases linearly with the logarithm of the frequency in the range 3.95 MHz to 11 MHz.







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Limit for radiated emissions at frequencies up to 1 GHz for class A EDM and arc welding equipment

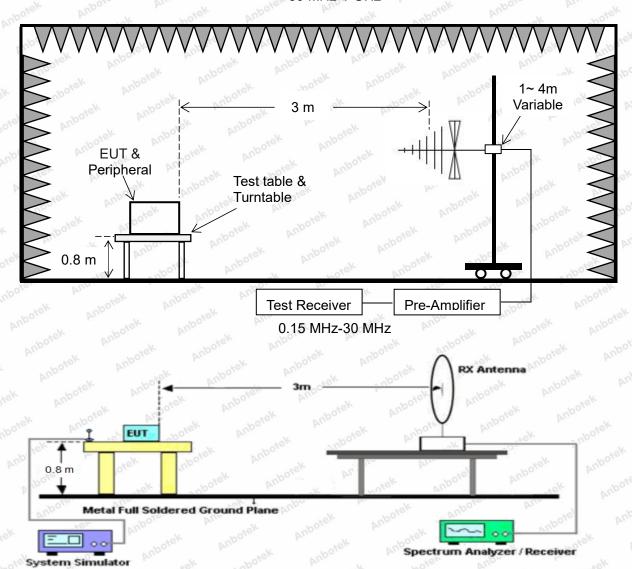
Frequency (MHz)	Distance (Meters)	Field Strengths Limit (dBμV/m)
30 ~ 230	hotek Anb 3°k Anbon	90 ~ 70*
230 ~ 1000	Ambotek Agorek Anbo	A Nobolek 70 Mibole A

Remark:

The limit decreases linearly with the logarithm of the frequency in the range 30 MHz to 230 MHz.

3.2. Test Setup

30 MHz-1 GHz



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3.3. Test Procedure

The table-top EUT is placed on a non-conductive table 0.8 m above the horizontal ground reference plane. The floor-standing EUT is placed on an insulating support 0.1 m above the horizontal ground reference plane.

The EUT was set 3 m away from the receiving antenna that was mounted on a non-conductive mast. The antenna can move up and down between 1 to 4 m to find out the maximum emission level (The height of the loop antenna is fixed at 1.5m).

The turntable can rotate 360 degree to determine the position of the maximum emission level.

The initial testing identified the frequency that has the highest disturbance relative to the limit while operating the EUT in typical modes of operation and cable positions in a test setup representative of typical system configuration.

The identification of the frequency of highest emission with respect to the limit was found by investigating emissions at a number of significant frequencies. The probable frequency of maximum emission had been found and that the associated cable and EUT configuration and mode of operation had been identified.

In the test frequency range of 0.15MHz-30MHz, the analytical bandwidth of the receiver is set to 9KHz, and in the test frequency range of 30MHz-1000MHz, the analytical bandwidth of the receiver is set to 120KHz.

3.4. Test Results

PASS

The test curves are shown in the following pages.







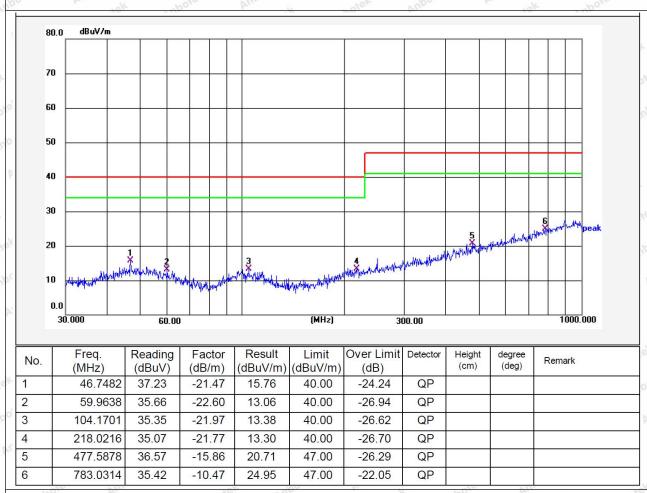
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Test item: Radiation Test Polarization: Horizontal

Standard: (RE)EN IEC 61326-1 Power Source: AC 400V, 50Hz

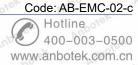
Frequency Range: 30MHz ~ 1000MHz Temp.($^{\circ}$)/Hum.($^{\circ}$ RH): 23.5($^{\circ}$)/49%RH

Distance: 3m



Note: Result= Reading + Factor Over Limit=Result-Limit









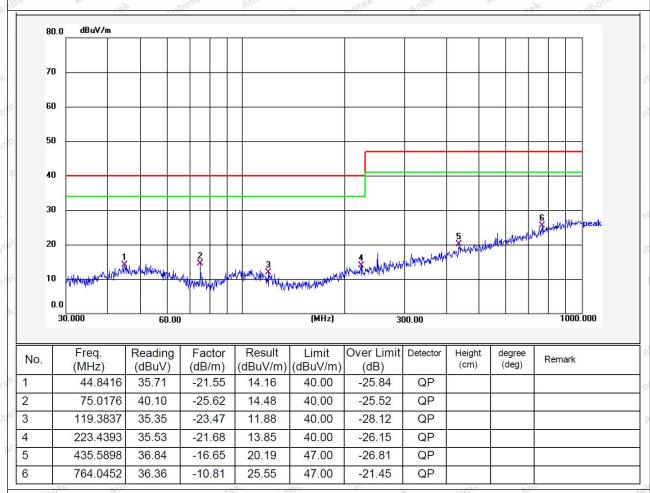
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Test item: Radiation Test Polarization: Vertical

Standard: (RE)EN IEC 61326-1 Power Source: AC 400V, 50Hz

Frequency Range: 30MHz ~ 1000MHz Temp.(°C)/Hum.(%RH): °C)/49%RH 23.5(

Distance: 3m



Result= Reading + Factor Over Limit=Result-Limit Note:









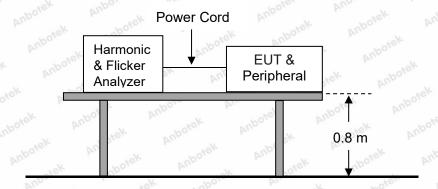
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4. Harmonic Current Test

4.1. Test Standard

_	127		- LAU	 	
4	Test Standard:	EN IEC 61000-3-2			Ar.

4.2. Test Setup

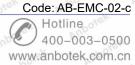


4.3. Test Procedure

The table-top EUT is placed on the top of a wooden table 0.8 m above the ground (0.1 m for the floor-standing EUT) and operated to produce the maximum harmonic components under normal operating conditions for each successive harmonic component in turn. The correspondent test program of test instrument to measure the current harmonics emanated from EUT is chosen. The measure time shall be not less than the necessary for the EUT to be exercised.

4.4. Test Results

PASS







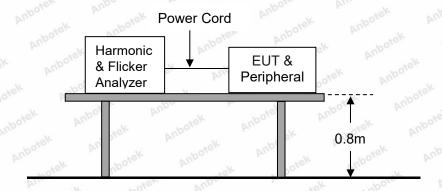
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5. Voltage Fluctuations & Flicker Test

5.1. Test Standard

T+ 0+	EN 04000 0 0	Aupo	*ek	Sports	D'U
Test Standard:	EN 61000-3-3	hotek	Aupo,	Ar.	nbot

5.2. Test Setup



5.3. Test Procedure

The table-top EUT is placed on the top of a wooden table 0.8 m above the ground (0.1 m for the floor-standing EUT) and operated to produce the most unfavorable sequence of voltage changes under normal conditions during the flicker measurement. The observation period for short-term flicker indicator is 10 minutes and the observation period for long-term flicker indicator is 2 hours.

5.4. Test Results

PASS







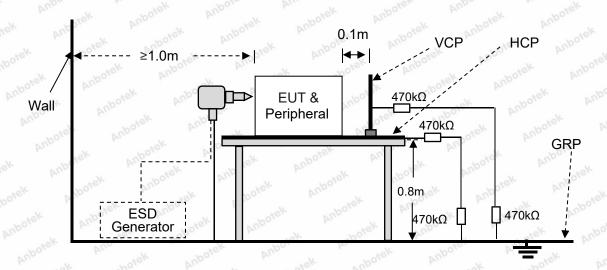
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6. Electrostatic Discharge Immunity Test

6.1. Test Specification

N _e	Test Standard :	EN IEC 61326-1
,0	Basic standard :	IEC 61000-4-2: 2008
	Performance criteria:	bek Aupore Am Anbotek Anbotek Anbotek
ΥZ	Test Level :	± 8kV (Air Discharge) ± 4kV (Contact Discharge)

6.2. Test Setup



6.3. Test Procedure

- a. In the case of air discharge testing, the climatic conditions shall be within the following ranges:
- Ambient temperature: 15°C to 35°C;
- Relative humidity: 30% to 60%;
- Atmospheric pressure: 86 kPa (860 mbar) to 106 kPa (1060 mbar)
- b. In the case of contact discharges, the tip of the discharge electrode shall touch the EUT before the discharge switch is operated.
- c. In the case of painted surface covering a conducting substrate, the following procedure shall be adopted: If the coating is not declared to be an insulating coating by the equipment manufacturer, then the pointed tip of the generator shall penetrate the coating so as to make contact with the conducting substrate. Coating declared as insulating by the manufacturer shall only be submitted to the air discharge. The contact discharge test shall not be applied to such surfaces.

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d. In the case of air discharges, the round discharge tip of the discharge electrode shall be approached as fast as possible (without causing mechanical damage) to touch the EUT. After each discharge, the ESD generator (discharge electrode) shall be removed from the EUT. The generator is then retriggered for a new single discharge. This procedure shall be repeated until the discharges are completed. In the case of an air discharge test, the discharge switch, which is used for contact discharge, shall be closed.

- e. The test voltage shall be increased from the minimum to the selected test severity level, in order to determine any threshold of failure. The final test level should not exceed the product specification value in order to avoid damage to the equipment.
- f. The test shall be performed with both air discharge and contact discharge. The test shall be performed with single discharges. On each pre-selected point at least 10 single discharges (in the most sensitive polarity) shall be applied. For the time interval between successive single discharges an initial value of 1 s is recommended. Longer intervals may be necessary to determine whether a system failure has occurred.
- g. Ensure that the applied charge on the EUT has been dis-charged before next ESD pulse.

6.4. Test Results

PASS

Please refer to the following page.







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Electrostatic Discharge Test Results

Test Result:	⊠ Pass □ Fail	Temperature:	18.9℃
Power Supply:	AC 400V, 50Hz	Humidity:	47%
-k hotek Anb	oter Ando tek	anbotek Anbote A	hotek Anborek An
Anbotek Anbotek Lo	ocation	Kind A-Air Dischar C-Contact Disch	78,
Air discharge: ±2.0 kV, ±4	0 kV, ±8.0 kV	Contact discharge	: ±4.0 kV
Slot Anborek Anbor	4 points	botek Anbotek A An	⊠A □B □C
Button	4 points	Amborek Amborek	⊠A □B □C
Screen	4 points	Anbotek Anbotek	⊠A □B □C
HCP Anbotek Anbotek	4 points	ak phoofek C Anbor	⊠A □B □C
VCP of the front	4 points	Botek Ambotek C Anh	⊠A □B □C
VCP of the rear	4 points	Anborek Anborek C	⊠A □B □C
VCP of the left	4 points	Aupotek Pupotek	⊠A □B □C
VCP of the right	4 points	k Anbore C Anbore	⊠A □B □C
Anbotek Anbo	k Anbotek Anb	ore Anborek Anb	otek Anbotek Anbo
Note: N/A			





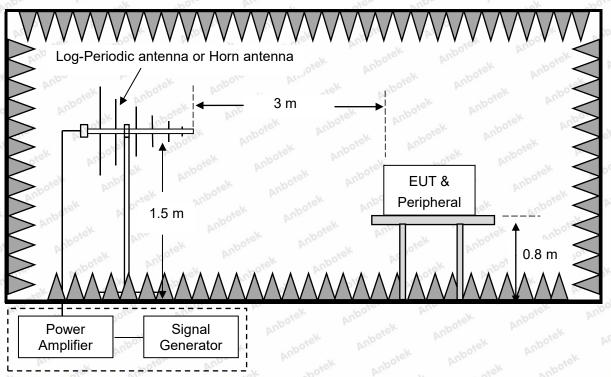
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7. RF Field Strength Immunity Test

7.1. Test Specification

14	Test Standard:	EN IEC 61326-1		
	Basic standard:	IEC 61000-4-3: 2020	stek Anbo. K hotek Anbote. Anb	
0		□ Basic Requirements	80MHz - 1GHz & 3V/m; Performance criteria:A 1.4GHz - 6GHz & 3V/m; Performance criteria:A	
	Test level:	☐ Requirements for industrial sites	80MHz - 1GHz & 10V/m; Performance criteria:A 1.4GHz - 6GHz & 3V/m; Performance criteria:A	
2.		☐ Requirements for controlled electromagnetic environment	80MHz - 1GHz & 1V/m; Performance criteria:A 1.4GHz - 6GHz & 1V/m; Performance criteria:A	
	Modulation:	1kHz Sine Wave, 80%, AM	Modulation	
13	Frequency Step:	1 % of preceding frequency	value	
	Polarity of Antenna:	Horizontal and Vertical	botek Anbore And Otek Anborek	
	Test Distance:	3 m	And Anborek Anbo	
	Antenna Height:	1.5 m	And tek abotek Anbor Anbor	
	Dwell Time:	at least 0.5s	ek Anbo, Ar Potek Aupote, Anb	
3.6	Aug	upotek Anbo. A.	potek Anbote Anti-	

7.2. Test Setup



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7.3. Test Procedure

The procedure defined in this part requires the generation of electromagnetic fields within which the test sample is placed and its operation observed. To generate fields that are useful for simulation of actual (field) conditions may require significant antenna drive power and the resultant high field strength levels. To comply with local regulations and to prevent biological hazards to the testing personnel, it is recommended that these tests be carried out in a shielded enclosure or semi-anechoic chamber.

- a. The antenna is placed 3 m from the equipment. The required field strength is determined by placing the field strength meter(s) on top of or directly alongside the equipment under test and monitoring the field strength meter via a remote field strength indicator outside the enclosure while adjusting the continuous-wave to the antenna.
- b. The test shall normally be performed with the generating antenna facing each side of the EUT. When equipment can be used in different orientations (i.e. vertical or horizontal) all sides shall be exposed to the field during the test. When technically justified, some EUTs can be tested by exposing fewer faces to the generating antenna. In other cases, as determined for example by the type and size of EUT or the frequencies of test, more than four azimuths may need to be exposed.
- The polarization of the field generated by each antenna necessitates testing each selected side twice,
 once with the antenna positioned vertically and again with the antenna positioned horizontally.
- d. The step size of the frequency is set to 1%. The dwell time at each frequency shall not be less than the time necessary for the EUT to be exercised and to be able to respond. However, the dwell time should not exceed 5 s at each of the frequencies during the scan.

7.4. Test Results

PASS

Please refer to the following page.







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RF Field Strength Susceptibility Test Results

Test Result:	⊠ Pass	s 🗌 Fail	Temperature:	20.1℃	otek Anbotek
Power Supply:	AC 400\	V, 50Hz	Humidity:	49%	abotek Anbot
tek Aupo,	potek.	Anbores And	tek anbotek	Anbo.	hotek Ar
Frequency Range	Antenna Polarity	R.F. Field Strength	Dwell Time	Azimuth	Result
Anbotek Anbo	otek Anbo		Ann	Front Mario	stek Anbotek
80 MHz ~ 1000	H/V	☐ 10 V/m ⊠ 3 V/m	1s	Rear	⊠ A □ B
MHz	nbotek	☐ 1 V/m	potek Anbotek	Left	С
botek Anbur	Anbotek	Anbore An	Anbotek Anbot	Right	Anbotek
Anbotek Anbote	K Anbore		Anbotek An	Front	k Anbore
A A OHDOTEK	otek Anbe	⊠ 3 V/m	Anbore	Rear	⊠ A
1.4 GHz ~ 6 GHz	H/V	☐ 1 V/m	Anbotek Anbotek	Left	☐ C
potek Anbotek	Anbo		ore Annapote	Right	Anbo
Note: N/A	Anbotek	k Anbotek	Anbotek Ant	otek Anbotek	k Anbotek





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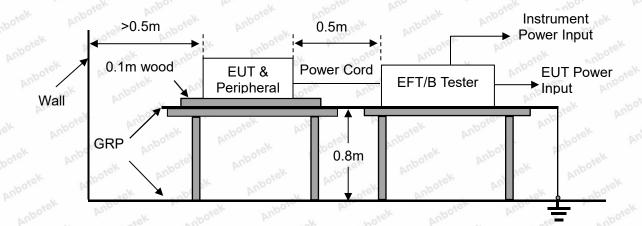
8. Electrical Fast Transient/Burst Immunity Test

8.1. Test Specification

Test Standard:		EN IEC 61326-1
Basic standard:		IEC 61000-4-4: 2012
Performance criteria:		B abotek Anbotek Anbotek Anbotek Anbotek
3		□ 1 kV, AC mains power ports
		☐ 1 kV, DC power ports
		□ 0.5 kV, I/O ports(Including functional earth)
		☐ 1 kV, I/O ports(Connected directly to mains supply)
		☐ 2 kV, AC mains power ports
Test Level	☐ Requirements for industrial sites	☐ 2 kV, DC power ports
LOVOI		☐ 1 kV, I/O ports(Including functional earth)
		☐ 2 kV, I/O ports(Connected directly to mains supply)
	Requirements for controlled electromagnetic environment	□ 1 kV, AC mains power ports
		☐ 1 kV, DC power ports
		□ 0.5 kV, I/O ports(Including functional earth)

8.2. Test Setup

AC mains power ports and DC network power ports:





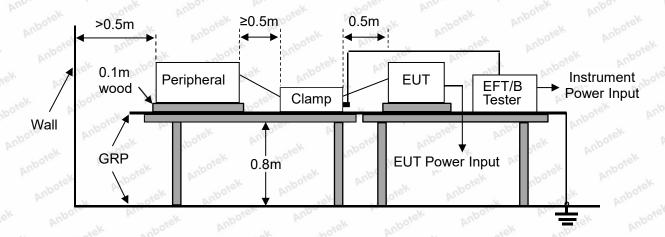




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I/O ports:

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8.3. Test Procedure

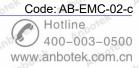
The table-top EUT is placed on a table that is 0.8 m height, a ground reference plane is placed on the table, and uses 0.1 m insulation between the EUT and ground reference plane. The floor-standing EUT is placed on a ground reference plane and insulated from it by an insulating support with a thickness of 0.1 m. This reference ground plane shall project beyond the EUT by at least 0.1 m on all sides and the minimum distance between EUT and all other conductive structure, except the ground plane beneath the EUT, shall be more than 0.5 m.

All cables to the EUT shall be placed on the insulation support 0.1 m above the ground reference plane. Cables not subject to electrical fast transients shall be routed as far as possible from the cable under test to minimize the coupling between the cables.

8.4. Test Results

PASS

Please refer to the following page.







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Electrical Fast Transient/Burst Test Results

Test Result:	⊠ Pass □	Fail Temperat	ure: Anbotek	18.6℃
Power Supply:	AC 400V, 50Hz	Humidity:	botek Anbote	47%
rek Anbe	abotek Anbote	Amotek	Anbotek Anbo	tek apolek Ar
Ports	Polarity	Inject Time(s)	Test Voltage (k	V) Result
⊠ AC mains power ports	tek #Ipotek	120 s		⊠A □B □C
☐ DC power ports	Proposek + Vipotek	120 s	☐ 1.0 kV ☐ 2.0 kV	□A □B □C
☐ I/O ports	Anbore Ans	120 s	□ 0.5 kV □ 1.0 kV	□A □B □C
Note: N/A	ek Anborek	Anbotek Anbote	otek Anbotek	Anbotek Anbote





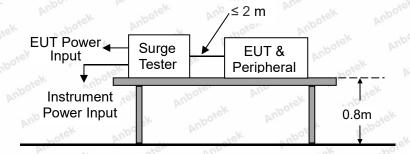
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9. Surge Immunity Test

9.1. Test Specification

Test Standard: EN IEC 61326-1		EN IEC 61326-1
	Basic standard:	IEC 61000-4-5: 2014+A1:2017
Performance criteria:		Bk Anborek Anbore Anborek Anborek Anborek
	⊠ Basic Requirements	 △ AC mains power ports; Line - Line/0.5KV; Line - Ground/1KV □ DC power ports; Line - Line/0.5KV; Line - Ground/1KV □ I/O ports(Including functional earth); Line - Ground/1KV
3		□ I/O ports(Connected directly to mains supply); Line - Line/0.5KV; Line - Ground/1KV
Test	Test evel: Requirements for industrial sites	□ AC mains power ports; Line - Line/1KV; Line - Ground/2KV□ DC power ports; Line - Line/1KV; Line - Ground/2KV
level:		☐ I/O ports(Including functional earth); Line - Ground/1KV
		☐ I/O ports(Connected directly to mains supply); Line - Line/1KV; Line - Ground/2KV
Requirements for controlled electromagnetic environment AC mains power ports; Line - Line/0.5KV		☐ AC mains power ports; Line - Line/0.5KV; Line - Ground/1KV
Number of surges		5 (for each combination of parameters)
Repetition rate Polarity: Phase angle:		1 minute / time
		Positive / Negative
		90°, 270° (Only AC mains power ports)

9.2. Test Setup









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9.3. Test Procedure

Table-top EUT is placed on a table of 0.8 m heights above a metal ground reference plane. Floor standing EUT is placed on a ground reference plane and insulated from it by an insulating support with a thickness of 0.1 m. The length of the power cord between the EUT and the coupling/decoupling network is not more than 2 m, and the length of the interconnection line between the EUT and the coupling/decoupling network is not more than 2 m. The tests were done at repetition rate 1 per minute.

9.4. Test Results

PASS

Please refer to the following page.





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Surge Immunity Test Results

200	V 5070	Ville	494	100	-V 1070
Test Result:	⊠ Pass	s ☐ Fail	Temperature :	18.6℃	botek Anbotek
Power Supply :	AC 400\	/, 50Hz	Humidity :	47%	Anbotek Anbo
botek Anbore	ik vupotek	Anboten Ar	botek Anbot	ek Anbore	Anborek
Location	Polarity	Phase Angle	Number of Pulse	Pulse Voltage (kV)	Result
	inborek An		ek Anbotek		
L1 - L2	Anbetek	⊠ 0° ⊠ 90° ⊠ 180° ⊠ 270°	ootek 5 Anbotek	⊠ 0.5 kV □ 1 kV	⊠A□B□C
Anbotek Anbotek	otek Anbotek	⊠ 0° ⊠ 90° ⊠ 180° ⊠ 270°	Anbote 5 Ant	⊠ 0.5 kV □ 1 kV	⊠A□B□C
L1 - L3	nbotek + Anbot	⋈ 0°⋈ 90°⋈ 180°⋈ 270°	5	⊠ 0.5 kV □ 1 kV	⊠A□B□C
k Aupolek	Anborek An	⋈ 0°⋈ 90°⋈ 180°⋈ 270°	otek 5 Anbotek	⊠ 0.5 kV □ 1 kV	⊠A□B□C
L2 - L3	, Aphotek	⊠ 0° ⊠ 90° ⊠ 180° ⊠ 270°	Anborek 5 Anbore	⊠ 0.5 kV □ 1 kV	⊠A□B□C
Anbores L3	upotek - Aupote	⊠ 0° ⊠ 90° ⊠ 180° ⊠ 270°	Anba 5 k	⊠ 0.5 kV □ 1 kV	⊠A□B□C
L1 - GND -	Anbotek Anb	⋈ 0°⋈ 90°⋈ 180°⋈ 270°	5 5	□ 1 kV □ 2 kV	⊠A□B□C
L1 - GND	Anbotek Anbotek	⋈ 0°⋈ 90°⋈ 180°⋈ 270°	mbolek 5 Ambole	□ 1 kV □ 2 kV	⊠A□B□C
Anbotek Anbo	rek + Anboren	⋈ 0°⋈ 90°⋈ 180°⋈ 270°	5		⊠A□B□C
L2 - GND	Anbotek Anbo	⊠ 0° ⊠ 90° ⊠ 180° ⊠ 270°	Ar 5° hek	⊠ 1 kV □ 2 kV	⊠A□B□C
tek Ambotek	Anbotek A	⋈ 0°⋈ 90°⋈ 180°⋈ 270°	tek Anboten 5 Anbotek	□ 1 kV □ 2 kV	⊠A□B□C
L3 - GND -	ek Aupotek	⊠ 0° ⊠ 90° ⊠ 180° ⊠ 270°	Amborek 5 Ambo	□ 1 kV □ 2 kV	⊠A□B□C
Anbotek An	potek + Anbore	∅°№ 90°№ 180°№ 270°	5 tek		⊠A□B□C
N - GND	Anbotek An	⊠ 0° ⊠ 90° ⊠ 180° ⊠ 270°	5 borek	⊠ 1 kV	⊠A□B□C

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□ DC power po	rts Anboten	Anbarrek		ek abotek	Anboren
Anbor P - N Anbo	tek ±nbotek	Andotek	Anborek 5	□ 0.5 kV □ 1 kV	□A□B□C
P - GND	Whotek + Who	rek Anbotek	And Stek	☐ 1 kV ☐ 2 kV	□A□B□C
N - GND	Anbotek Ar	Anborek / Anbo	5 Anborek	☐ 1 kV ☐ 2 kV	□A□B□C
☐ I/O ports					
Nibotek Anbo	+ botek	Anlepten	And 5	1KV	□A□B□C
Lines to ground	bo, by	ek Yupoter	And 5	1KV	□A□B□C
☐ I/O ports	Anbo. Ack At.	botek Anbotes	K And Potek	Anbotek An	oo, ky upot
Line to Line	Anborek Ar	Anbotek / Anbot	potek 5 Anbotek	□ 0.5 kV □ 1 kV	□A□B□C
Line to ground	ek #botek	Anboyek Anboyek	Anbotek 5 Anbot	☐ 1 kV ☐ 2 kV	□A□B□C
Note: N/A	por Air	ek Anbotek	Anb	Anborek Anbor	ak abotek





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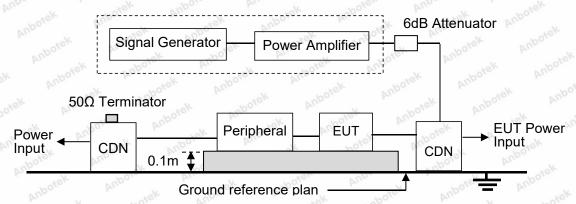
10. Injected Currents Susceptibility Test

10.1. Test Specification

Test Standard:		EN IEC 61326-1
Basic standard:		IEC 61000-4-6: 2013
Performance criteria:		A botek Anbotek Anbotek Anbotek Anbotek
Frequency range:		0.15MHz - 80MHz
4.	☐ Basic Requirements	3V Anborek Anborek Anborek Anborek Anbor
Test level:		3V Anbotek Anbotek Anbotek Anbotek Anbotek
	☐ Requirements for controlled electromagnetic environment	Totek Anbotek Anbotek Anbotek Anbotek Anbotek Anbotek Anbotek Anbotek
Modulation:		AM 80%, 1kHz sine-wave
Frequency Step:		1% of fundamental

10.2. Test Setup

CDN injection:

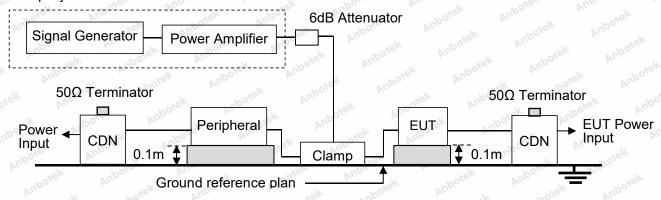






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Clamp injection:



10.3. Test Procedure

- a. The EUT and peripheral are placed on an insulating support of 0.1 m height above a ground reference plan. The distance between EUT and CDN is 0.1 m to 0.3 m. All cables exiting the EUT are supported at a height of at least 30 mm above the ground reference plan.
- b. The frequency range is swept from 150 kHz to 80MHz, with the signal 80% amplitude modulated with a 1 kHz sine wave. The rate of sweep did not exceed 1.5x 10-3 decade/s. The frequency range is swept incrementally. The step size was 1% of fundamental from 0.15MHz to 80MHz.
- c. The dwell time at each frequency isn't less than the time necessary for the EUT to be able to respond.

10.4. Test Results

PASS

Please refer to the following page.







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Injected Currents Susceptibility Test Results

Test Result:	⊠ Pass □ Fail	Temperature:	18.6℃	
Power Supply:	AC 400V, 50Hz	Humidity:	47%	
lek Aupo, ek h	otek Anbore, Anb	tek anbotek Anb	o. A. hotek Ar	
Frequency Range (MHz)	Injected Position	Voltage (Un-modulated)	Result	
Basic Requirements	Anbotek Anbotek	Anborek Anborek	Anbotek Anbote	
botek Anbote		Anbo sek shotel	Anbore Ans	
0.15 ~ 80	□ DC power	3V	□A □B □C	
er Aupo	☐ I/O ports	otek Anbotek Anb	ok shotek Ani	
Requirements for indu	ustrial sites	botek Anbotek A	upor Ali upotek	
Anbotek Anbo. ck	☐ AC Mains	And otek Anbotek	Anbo ok hotek	
0.15 ~ 80	☐ DC power	Andrew 3V	⊠A □B □C	
Ans stek subotek	☐ I/O ports	Anbore Ant atek	anbotek Anbo	
☐ Requirements for controlled electromagnetic environment				
ok Potek Pupo	☐ AC Mains	otek Anbo. A	botek Anbote An	
0.15 ~ 80	☐ DC power	hotek 1Vootek Af	□A □B □C	
subotek Ando Ak	☐ I/O ports	and	Anbe ok spotek	
Note: N/A	Anbotek Anbotek	Anbotek Anbotek	Anbore Anborek	





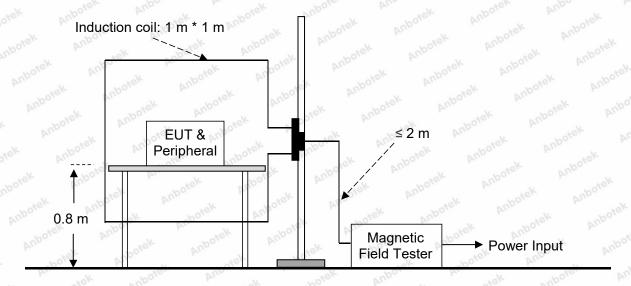
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11. Power Frequency Magnetic Field Immunity Test

11.1. Test Specification

1227.	5, 10,	, po-	V/8, VU
Test Standard:	EN IEC 61326-1		Aupo tek
Basic Standard	IEC 61000-4-8: 2009	hotek Anbotek	Aupo, Air
Performance criteria	A tek hotek Arbote	And hotek Anbotek	Anbo. Lek
Test level	⊠ Basic Requirements	3 A/m	er Anbo
rest level	☐ Requirements for industrial sites	30 A/m	poter Ando

11.2. Test Setup



11.3. Test Procedure

Table-top EUT is placed on a table that is 0.8 m height. Floor standing EUT is placed on a ground reference plane and insulated from it by an insulating support with a thickness of 0.1 m.

The EUT is placed in the middle of an induction coil. The proximity method is used when the EUT does not fit into the standard inductive coil

11.4. Test Results

PASS

Please refer to the following page.

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Magnetic Field Immunity Test Results

Test Result:	⊠ Pass ☐ Fail	Temperature :	18.6℃
Power Supply :	AC 230V, 50Hz	Humidity:	47%
Basic Requirements ■	otek Anboie Am	notek Anbotek Anb	ek abotek Ar
Test Level (A/M)	Testing Duration	Coil Orientation	Result
Anborek 3 Anborek	5 minutes	Anbotek X Anbotek	⊠A □B □C
Anbotek 3 Anbotek	5 minutes	Anbore Y Anborel	⊠A □B □C
ek Anbotek Anbo	5 minutes	otek Andrek Anb	⊠A □B □C
ootek Anbor An	nbotek Anbotek An	Anbotek Anbotek A	hoo, Anbotek
Requirements for ind	ustrial sites	upotek Anbors	An hotek Anbotek
Test Level (A/M)	Testing Duration	Coil Orientation	Result
30	5 minutes	Anbotek Anbo	□A □B □C
otek Mage Aup	5 minutes	otek Anbotek Ar	□A □B □C
Inposes 30 poses	5 minutes	Anborek Z Anborek	□A □B □C
Note: N/A	Anbotek Anbotek	Anbotek Anbotek	Anbotek Anbotek





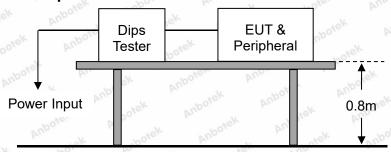
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12. Voltage Dips and Interruptions Immunity Test

12.1. Test Specification

Test Standard:	EN IEC 61326-1	Anb Lak shorek Anboth An	
Basic standard:	IEC 61000-4-11: 2020	Anbor Anbores Anbores Anb	
	potek Anbo, ok h	⊠ 0%, 0.5 period, Criterion B	
	□ Basic Requirements	⊠ 0%, 1 periods, Criteria B	
Test level:		⊠ 70%, 25 periods, Criteria C	
		⊠ 0%, 250 periods, Criteria C	
	Anbo, K. Mills Motek	□ 0%, 1 period, Criterion B	
	☐ Requirements for	☐ 40%, 10 periods for 50Hz, Criteria C	
	industrial sites	☐ 70%, 25 periods for 50Hz, Criteria C	
	Proper Aupo	□ 0%, 250 periods for 50Hz, Criteria C	

12.2. Test Setup



12.3. Test Procedure

- a. Where the equipment has a rated voltage the following shall apply:
- If the voltage range does not exceed 20% of the lower voltage specified for the rated voltage range, a single voltage within that range may be specified as a basis for test level specification.
- In all other cases, the test procedure shall be applied for both the lowest and highest voltages declared in the voltage range.
- b. Test Conditions
- Select operated voltage and frequency of EUT Test of interval: 10 sec.
- Level and duration: Sequence of 3 dips/interrupts.
- Voltage rise (and fall) time: 1.5 μs.
- c. Changes to occur at 0 degree crossover point of the voltage waveform.

12.4. Test Results

PASS







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APPENDIX I -- TEST SETUP PHOTOGRAPH

Photo of Power Line Conducted Emission Test

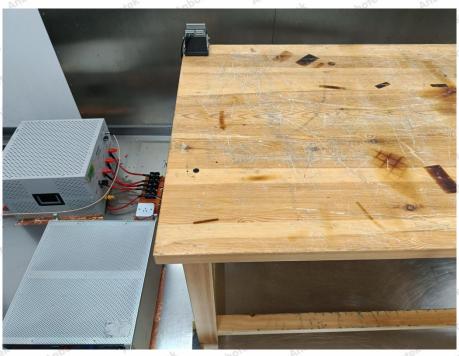


Photo of Radiated Emission Test (Below 1 GHz)



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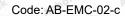




Photo of RF Field Strength Immunity Test



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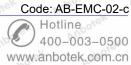


Photo of Surge Immunity Test



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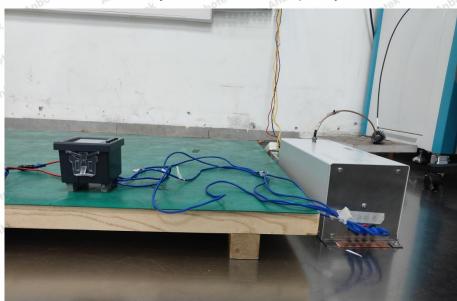
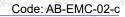


Photo of Injected Currents Susceptibility Test





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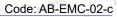
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APPENDIX II -- Photo documentation





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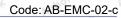


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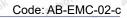


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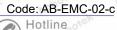


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CE Label

- The CE conformity marking must consist of the initials 'CE' taking the following form:
 If the CE marking is reduced or enlarged, the proportions given in the above graduated drawing must be respected.
- 2. The CE marking must have a height of at least 5 mm except where this is not possible on account of the nature of the apparatus.
- 3. The CE marking must be affixed to the product or to its data plate. Additionally it must be affixed to the packaging, if any, and to the accompanying documents.
- 4. The CE marking must be affixed visibly, legibly and indelibly.

 It must have the same height as the initials 'CE'.

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